

CSD19538Q2 100V N 沟道 NexFET™ 功率 MOSFET

1 特性

- 超低 Q_g 和 Q_{gd}
- 低热阻
- 雪崩级
- 无铅
- 符合 RoHS
- 无卤素
- SON 2mm × 2mm 塑料封装

2 应用

- 以太网供电 (PoE)
- 电源设备 (PSE)
- 电机控制

说明

这款 100V 49mΩ 2mm x 2mm SON NexFET™ 功率 MOSFET 旨在用于更大限度地降低功率转换应用中的损耗。

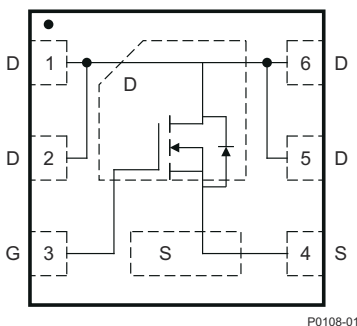
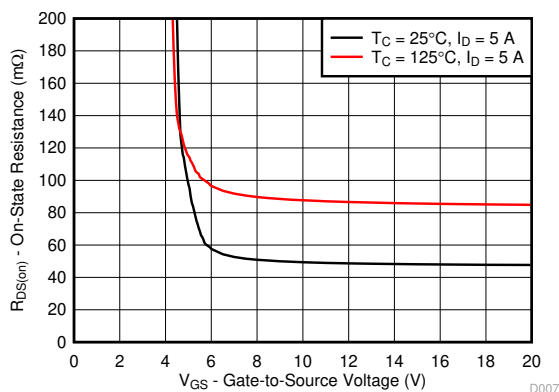


图 3-1. 顶视图



$R_{DS(on)}$ 与 V_{GS} 之间的关系

产品概要

| $T_A = 25^\circ C$ | | 典型值 | | 单位 |
|--------------------|--------------|----------------|----|----|
| V_{DS} | 漏源电压 | 100 | | V |
| Q_g | 栅极电荷总量 (10V) | 4.3 | | nC |
| Q_{gd} | 栅极电荷 (栅极到漏极) | 0.8 | | nC |
| $R_{DS(on)}$ | 漏源导通电阻 | $V_{GS} = 6V$ | 58 | mΩ |
| | | $V_{GS} = 10V$ | 49 | |
| $V_{GS(th)}$ | 阈值电压 | 3.2 | | V |

器件信息(1)

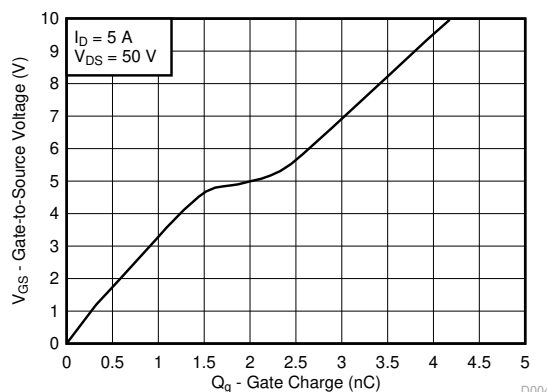
| 器件 | 数量 | 介质 | 封装 | 运输 |
|-------------|--------|---------|---|------|
| CSD19538Q2 | 3000 | 7 英寸卷带 | 无引线小外形尺寸 (SON) 2.00mm x 2.00mm 塑料封装 | 卷带包装 |
| CSD19538Q2T | 250 | | | |
| CSD19538Q2R | 10,000 | 13 英寸卷带 | | |

(1) 如需了解所有可用封装, 请参阅数据表末尾的可订购产品附录。

绝对最大额定值

| $T_A = 25^\circ C$ | | 值 | 单位 |
|----------------------|---|-----------|----|
| V_{DS} | 漏源电压 | 100 | V |
| V_{GS} | 栅源电压 | ±20 | V |
| I_D | 持续漏极电流 (受封装限制) | 14.4 | A |
| | 持续漏极电流 (受器件限制), $T_C = 25^\circ C$ 时测得 | 13.1 | |
| | 持续漏极电流(1) | 4.6 | |
| I_{DM} | 脉冲漏极电流(2) | 34.4 | A |
| P_D | 功率耗散(1) | 2.5 | W |
| | 功率耗散, $T_C = 25^\circ C$ | 20.2 | |
| T_J , T_{stg} | 工作结温, 贮存温度 | -55 至 150 | °C |
| E_{AS} | 雪崩能量, 单脉冲 $I_D = 12.6A$, $L = 0.1mH$, $R_G = 25\Omega$ | 8 | mJ |

- (1) 0.06 英寸厚 FR4 PCB 上 1 平方英寸、2oz. 铜焊盘上的 $R_{\theta JA} = 50^\circ C/W$ (典型值)。
- (2) 最大 $R_{\theta JC} = 6.2^\circ C/W$, 脉冲持续时间 $\leq 100 \mu s$, 占空比 $\leq 1\%$ 。



栅极电荷



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3 Specifications

3.1 Electrical Characteristics

T_A = 25°C (unless otherwise stated)

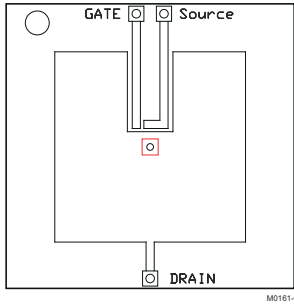
| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------------------------|----------------------------------|---|-----|------|------|------|
| STATIC CHARACTERISTICS | | | | | | |
| B _V DSS | Drain-to-source voltage | V _{GS} = 0V, I _D = 250 μA | 100 | | | V |
| I _{DSS} | Drain-to-source leakage current | V _{GS} = 0V, V _{DS} = 80V | | | 1 | μA |
| I _{GSS} | Gate-to-source leakage current | V _{DS} = 0V, V _{GS} = 20V | | | 100 | nA |
| V _{GS(th)} | Gate-to-source threshold voltage | V _{DS} = V _{GS} , I _D = 250 μA | 2.8 | 3.2 | 3.8 | V |
| R _{DS(on)} | Drain-to-source on resistance | V _{GS} = 6V, I _D = 5A | | 58 | 72 | mΩ |
| | | V _{GS} = 10V, I _D = 5A | | 49 | 59 | |
| g _{fs} | Transconductance | V _{DS} = 10V, I _D = 5A | | 19 | | S |
| DYNAMIC CHARACTERISTICS | | | | | | |
| C _{iss} | Input capacitance | V _{GS} = 0V, V _{DS} = 50V, f = 1MHz | | 349 | 454 | pF |
| C _{oss} | Output capacitance | | | 69 | 90 | pF |
| C _{riss} | Reverse transfer capacitance | | | 12.6 | 16.4 | pF |
| R _G | Series gate resistance | | | 4.6 | 9.2 | Ω |
| Q _g | Gate charge total (10V) | V _{DS} = 50V, I _D = 5A | | 4.3 | 5.6 | nC |
| Q _{gd} | Gate charge gate-to-drain | | | 0.8 | | nC |
| Q _{gs} | Gate charge gate-to-source | | | 1.6 | | nC |
| Q _{g(th)} | Gate charge at V _{th} | | | 1.0 | | nC |
| Q _{oss} | Output charge | V _{DS} = 50V, V _{GS} = 0V | | 12.3 | | nC |
| t _{d(on)} | Turnon delay time | V _{DS} = 50V, V _{GS} = 10V, I _D = 5A, R _G = 0Ω | | 5 | | ns |
| t _r | Rise time | | | 3 | | ns |
| t _{d(off)} | Turnoff delay time | | | 7 | | ns |
| t _f | Fall time | | | 2 | | ns |
| DIODE CHARACTERISTICS | | | | | | |
| V _{SD} | Diode forward voltage | I _{SD} = 5A, V _{GS} = 0V | | 0.85 | 1.0 | V |
| Q _{rr} | Reverse recovery charge | V _{DS} = 50V, I _F = 5A, | | 94 | | nC |
| t _{rr} | Reverse recovery time | di/dt = 300A/μs | | 32 | | ns |

3.2 Thermal Information

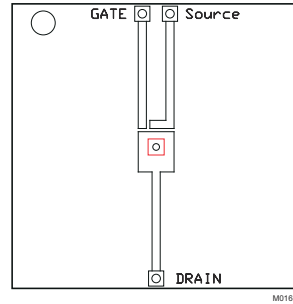
T_A = 25°C (unless otherwise stated)

| THERMAL METRIC | | MIN | TYP | MAX | UNIT |
|------------------|---|-----|-----|-----|------|
| R _{θJC} | Junction-to-case thermal resistance ⁽¹⁾ | | | 6.2 | °C/W |
| R _{θJA} | Junction-to-ambient thermal resistance ^{(1) (2)} | | | 65 | °C/W |

- (1) R_{θJC} is determined with the device mounted on a 1in² (6.45cm²), 2oz (0.071mm) thick Cu pad on a 1.5in × 1.5in (3.81cm × 3.81cm), 0.06in (1.52mm) thick FR4 PCB. R_{θJC} is specified by design, whereas R_{θJA} is determined by the user's board design.
- (2) Device mounted on FR4 material with 1in² (6.45cm²), 2oz (0.071mm) thick Cu.



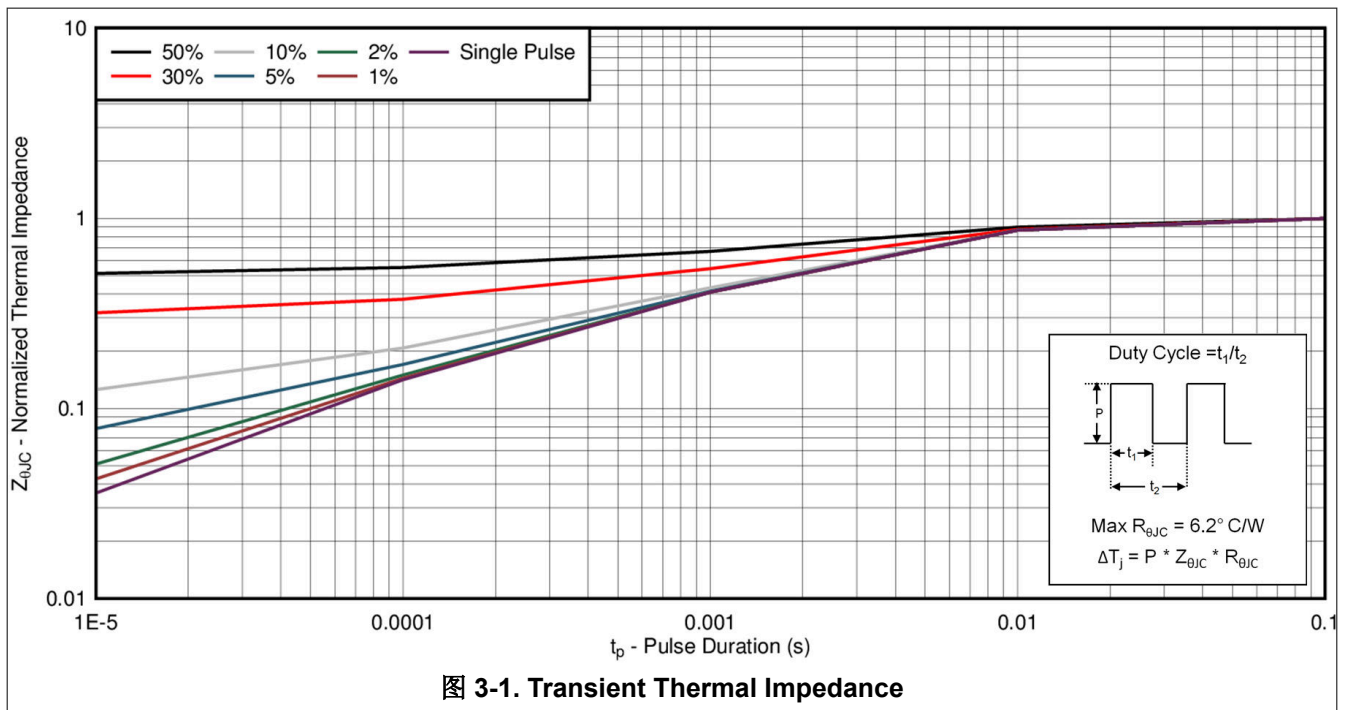
Max $R_{\theta JA} = 65^{\circ}\text{C/W}$ when mounted on 1in^2 (6.45cm^2) of 2oz (0.071mm) thick Cu.



Max $R_{\theta JA} = 250^{\circ}\text{C/W}$ when mounted on a minimum pad area of 2oz (0.071mm) thick Cu.

3.3 Typical MOSFET Characteristics

$T_A = 25^{\circ}\text{C}$ (unless otherwise stated)



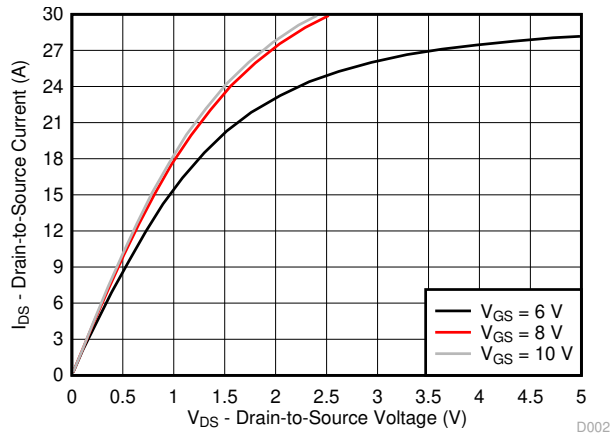


图 3-2. Saturation Characteristics

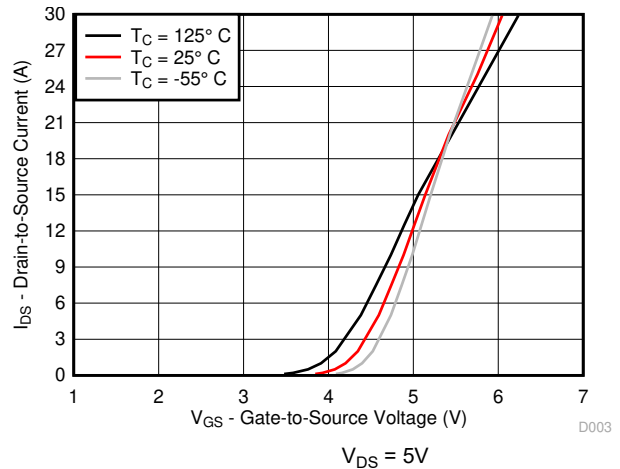


图 3-3. Transfer Characteristics

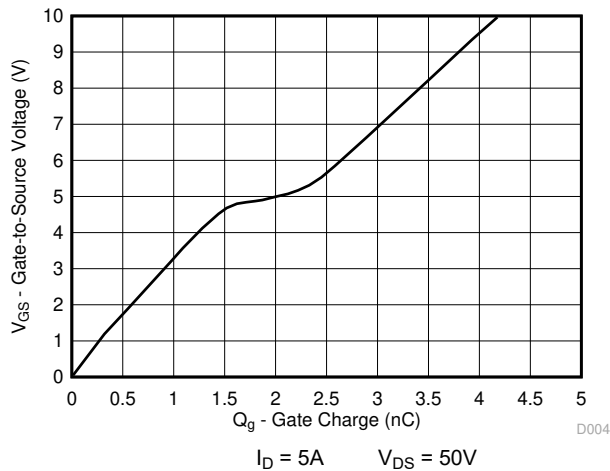


图 3-4. Gate Charge

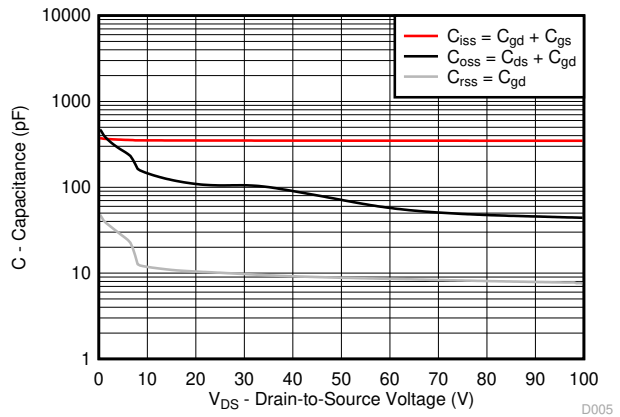


图 3-5. Capacitance

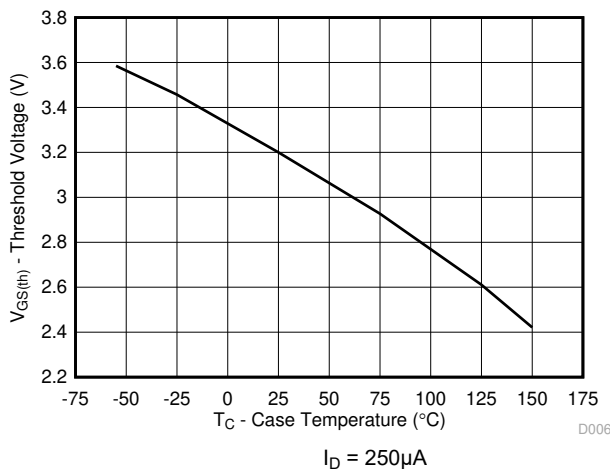


图 3-6. Threshold Voltage vs Temperature

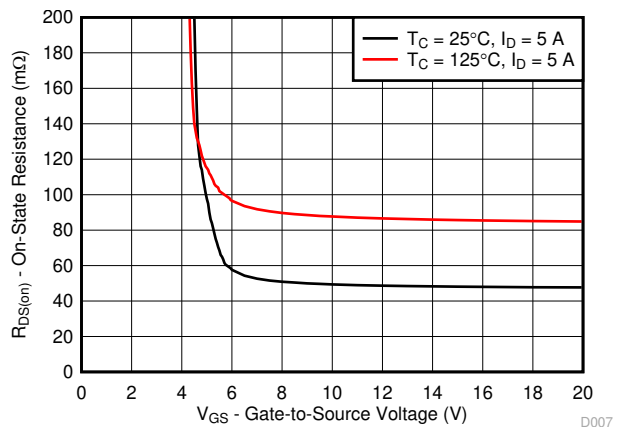


图 3-7. On-State Resistance vs Gate-to-Source Voltage

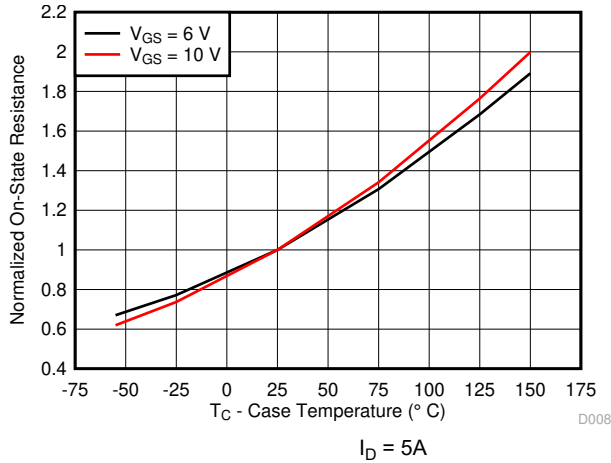


图 3-8. Normalized On-State Resistance vs Temperature

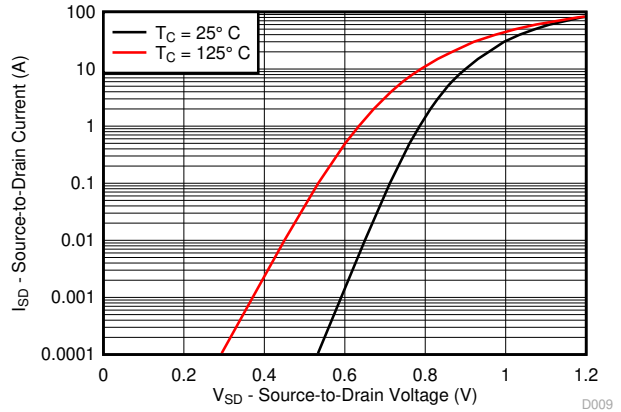


图 3-9. Typical Diode Forward Voltage

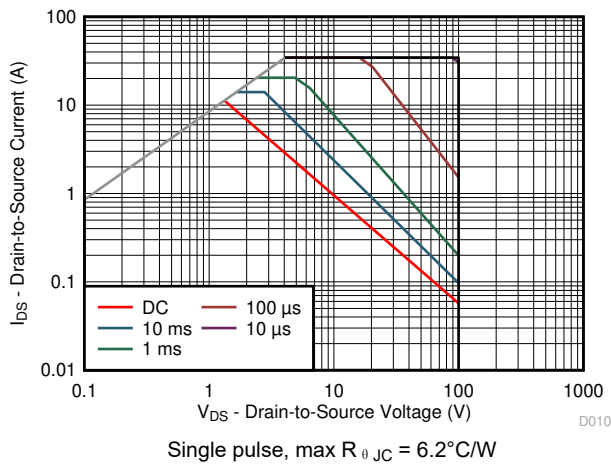


图 3-10. Maximum Safe Operating Area

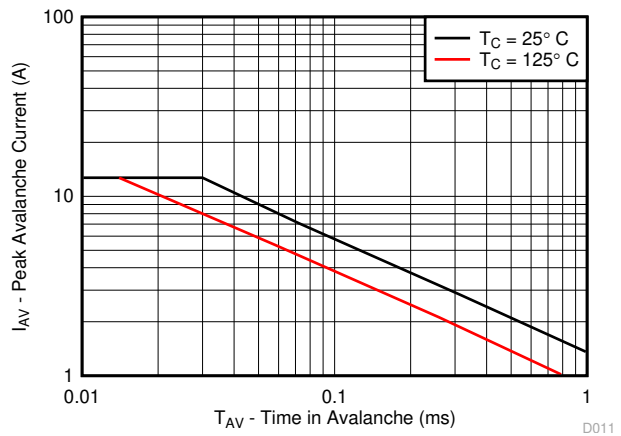


图 3-11. Single Pulse Unclamped Inductive Switching

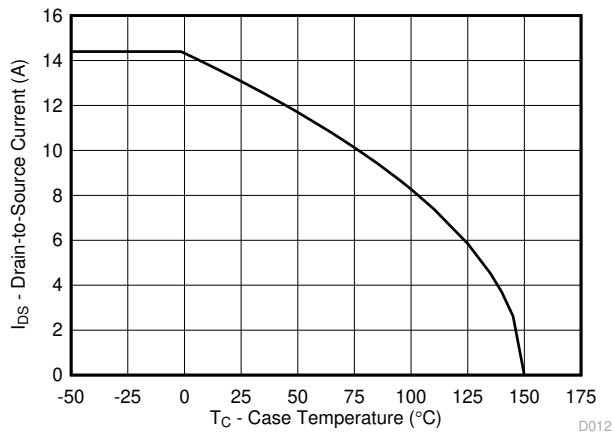


图 3-12. Maximum Drain Current vs Temperature

4 Device and Documentation Support

4.1 第三方产品免责声明

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要接收文档更新通知，请导航至 ti.com 上的器件产品文件夹。点击 [通知](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

4.3 支持资源

[TI E2E™ 中文支持论坛](#) 是工程师的重要参考资料，可直接从专家处获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题，获得所需的快速设计帮助。

链接的内容由各个贡献者“按原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的 [使用条款](#)。

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ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

4.6 术语表

[TI 术语表](#) 本术语表列出并解释了术语、首字母缩略词和定义。

5 Revision History

| Changes from Revision A (January 2017) to Revision B (March 2024) | Page |
|---|------|
| • 通篇更新了表格、图和交叉参考的编号格式..... | 1 |

| Changes from Revision * (July 2016) to Revision A (January 2017) | Page |
|---|------|
| • 将 图 3-2 曲线中的测试电压 V_{DS} 从 100V 更改为 50V..... | 1 |
| • Changed test voltage V_{DS} from 100V : to 50V in 图 3-4 | 4 |

6 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

| Orderable Device | Status (1) | Package Type | Package Drawing | Pins | Package Qty | Eco Plan (2) | Lead finish/ Ball material (6) | MSL Peak Temp (3) | Op Temp (°C) | Device Marking (4/5) | Samples |
|------------------|---------------|--------------|-----------------|------|-------------|-----------------|--------------------------------------|----------------------|--------------|-------------------------|-------------------------|
| CSD19538Q2 | ACTIVE | WSO | DQK | 6 | 3000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -55 to 150 | 1958 | Samples |
| CSD19538Q2R | ACTIVE | WSO | DQK | 6 | 10000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -55 to 150 | 1958 | Samples |
| CSD19538Q2T | ACTIVE | WSO | DQK | 6 | 250 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -55 to 150 | 1958 | Samples |

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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GENERIC PACKAGE VIEW

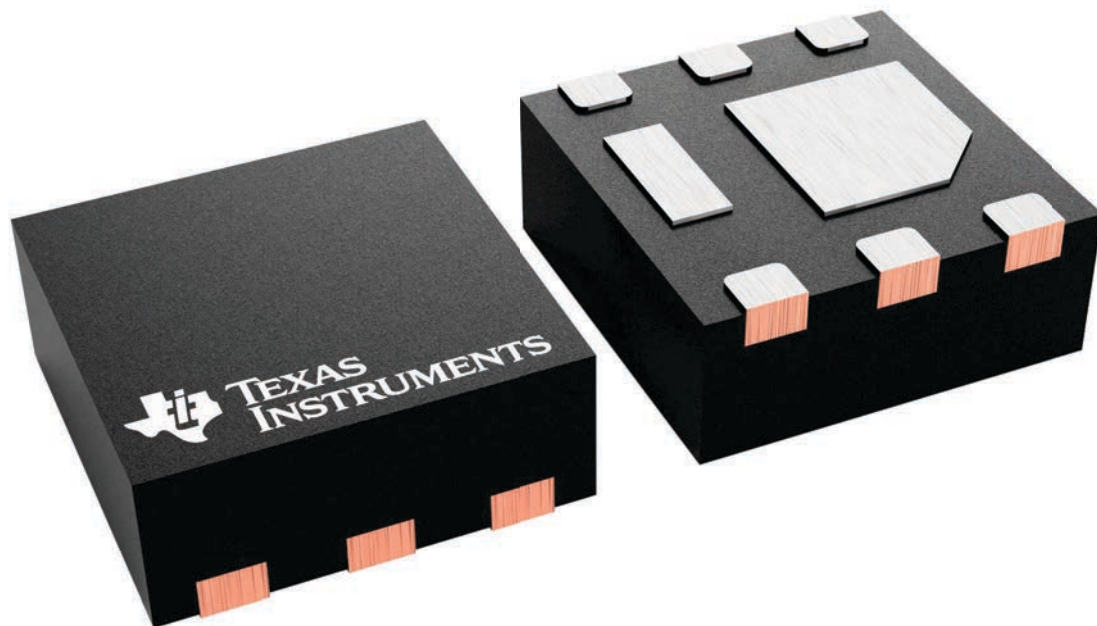
DQK 6

WSON - 0.8 mm max height

2 x 2, 0.65 mm pitch

PLASTIC SMALL OUTLINE - NO LEAD

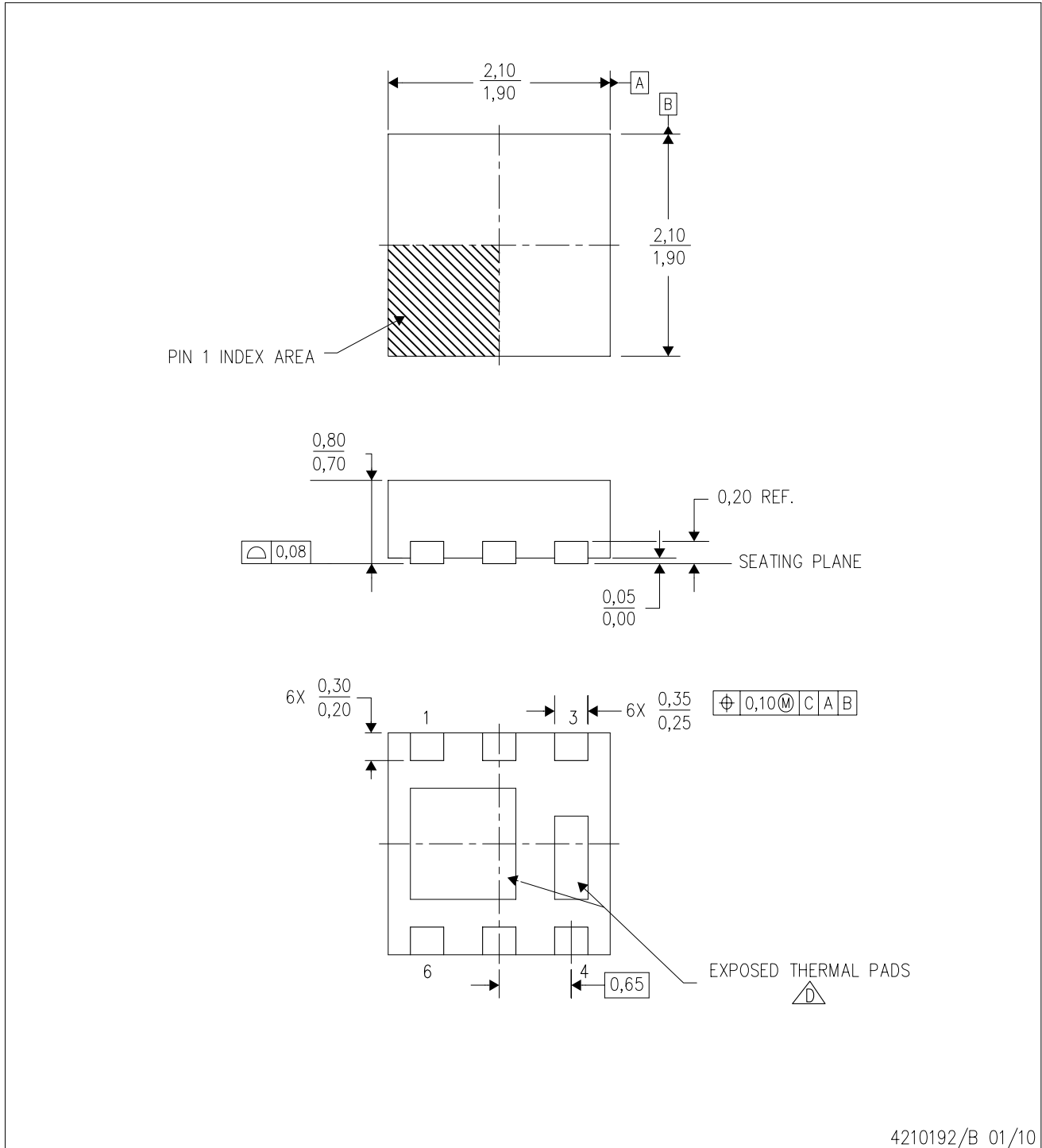
This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.




4229807/A

DQK (S-PWSON-N6)

PLASTIC SMALL OUTLINE NO-LEAD



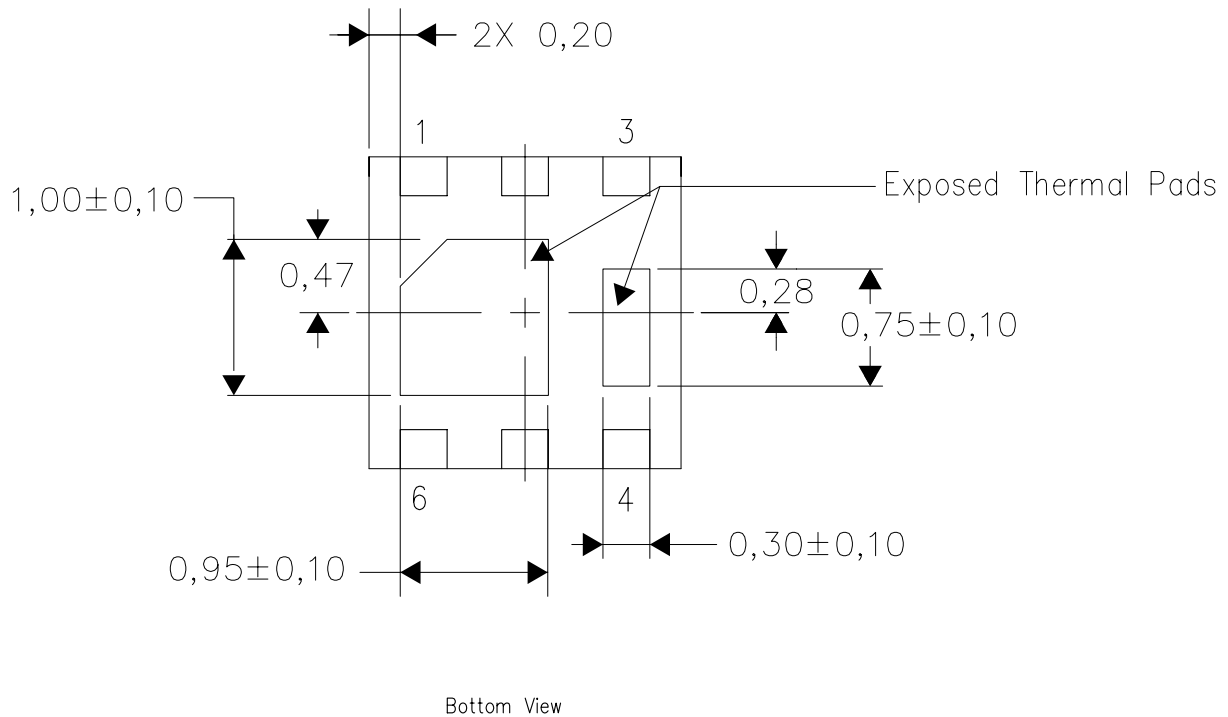
- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 - C. Small Outline No-Lead (SON) package configuration.
 -  D. The package thermal pads must be soldered to the board for thermal and mechanical performance.

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, Quad Flatpack No-Lead Logic Packages, Texas Instruments Literature No. SCBA017. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

重要声明和免责声明

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